

DEBATING THE FUTURE OF BURN-IN

Resolved: Burn-in will continue as the gold standard for identifying weak chips for the next decade or semi-decade

Moderator: Prof. Edward J. McCluskey, Center for Reliable Computing, Stanford University

Participants: Debators and the Audience

Debators:

Bob Madge, LSI Logic

Peter Maxwell, Agilent Technologies

Phil Nigh, IBM

Mike Rodgers, Intel Corporation

Organizers: Subhasish Mitra, Intel Corporation

Prof. E.J. McCluskey, Stanford University